Predictive Power of Two Data Flow Metrics in Software Defect Prediction

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- Keywords: Software Defect Prediction, Data Flow Metrics, Dep-Degree, Data Flow Complexity, Within-Project Defect Prediction.
- Abstract: Data flow coverage criteria are widely used in software testing, but there is almost no research on low-level data flow metrics as software defect predictors. *Aims:* We examine two such metrics in this context: dep-degree (DD) proposed by Beyer and Fararooy and a new data flow metric called dep-degree density (DDD). *Method:* We investigate the importance of DD and DDD in SDP models. We perform a correlation analysis to check if DD and DDD measure different aspects of the code than the well-known size, complexity, and documentation metrics. Finally, we perform experiments with five different classifiers on nine projects from the Unified Bug Dataset to compare the performance of the SDP models trained with and without data flow metrics. *Results:* 1) DD is noticeably correlated with many other code metrics, but DDD is not correlated or is very weakly correlated with other metrics considered in this study; 2) both DD and DDD are highly ranked in the feature importance analysis; 3) SDP models that use DD and DDD perform better than models that do not use data flow metrics. *Conclusions:* Data-flow metrics: DD and DDD can be valuable predictors in SDP models.

1 INTRODUCTION

Software defect prediction (SDP) is a widely investigated research area in software engineering. Many different SDP models were proposed, including within-project, cross-project, and just-in-time defect prediction (Kamei et al., 2013; Shen and Chen, 2020). Recent advances in the field focus on deep learning techniques and use different semantic representations of programs based on a given set of features, such as token vectors extracted from programs' Abstract Syntax Trees (Mikolov et al., 2013; Zhang et al., 2019; Shi et al., 2020). Another approach is to use the so-called hand-crafted features defined by experts. They characterize the statistical properties of the code, such as program size, complexity, code churn, or process metrics.

In modern approaches, extracting implicit structural, syntax, and semantic features from the source code is preferred over using explicit hand-crafted ones (Akimova et al., 2021). However, the classical code metrics should not be underestimated. First, contrary to the semantic features, hand-crafted features describe structural code complexity, which complements the semantic view. Second, classical code metrics are simple and easy to understand by a human. The models that use them are better explainable than models that use, for example, deep neural networks based on token vectors that have no meaning to the developer. Third, one of the key factors contributing to the difficulty of the SDP is the lack of context. As pointed out in (Akimova et al., 2021), unlike natural texts, the code element may depend on another element located far away, maybe even in another class, file, or component. Therefore, a simple metric that captures such relations could be very helpful as an additional feature in SDP models (for example, data flow metrics are widely used in automatic software vulnerability detection (Shen and Chen, 2020)).

Interest in data flow metrics comes from the hypothesis that defect proneness depends not only on the project structure or program semantics but also on the complexity of information flow that occurs in a module or system. Miller's hypothesis on the capacity to process information (Miller, 1956) suggests that the more dependencies a program operation has, the more different program states must be considered and the more difficult it is to understand the operation. When a developer writes or modifies a given line of code, there is a higher chance of error and of introducing a defect if the variables used in this line depend on more other places in the code.

114

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Research on data flow is still quite intensive in data flow testing, regarding the test coverage criteria, like all-defs, all-uses, all-du-paths, etc. (Ammann and Offutt, 2016; Hellhake et al., 2019; Neto et al., 2021; Kolchin et al., 2021). However, it does not seem to attract much attention from researchers in the context of SDP models. For example, popular bug databases like PROMISE (Sayyad Shirabad and Menzies, 2005), Eclipse (Zimmermann et al., 2007), GitHub Bug Dataset (Ferenc et al., 2020) use many different metrics, but none of them uses any kind of metric related to low-level data flow complexity, such as number of du-paths in the source code.

Therefore, it is not surprising that studies of SDP models also rarely use data flow metrics as independent variables. For example, just-in-time prediction models focus almost exclusively on process metrics (Kamei et al., 2013; Rahman and Devanbu, 2013). The most popular data flow-related concepts used in SDP research are some coarser features, like fanin and fan-out, calculated at the method level. In their survey article, Özakıncı and Tarhan (Özakıncı and Tarhan, 2018) refer to several SDP models and note that the only metric related to the data flow used in them is the 'data flow complexity' (Pandey and Goyal, 2009, 2013; Kumar and Yadav, 2017) defined by Henry and Kafura (Henry and Kafura, 1981), based on the above-mentioned features. The new papers focus mainly on deep learning methods and seem to disregard the concept of data flow. For example, (Shi et al., 2020) uses Code2vec (Alon et al., 2019) - one of the best source code representation models, which takes advantage of deep learning to learn automatic representations from code. One of the code characteristics used in (Shi et al., 2020) is the concept of path, but not related to data flow paths.

In 2010, a new data flow metric, called dep-degree (DD), was proposed (Beyer and Fararooy, 2010). The idea is to quantitatively describe the concept of socalled du-paths by counting the number of pairs (p,q) of nodes in the data flow graph for which there exists a path on which some variable is defined in p, used in q, and not redefined in between. This metric can be viewed as a more detailed version of the Oviedo metric, because it is based on the source code instructions, not on the basic blocks of code.

Akimova claims that hand-crafted features, like all above-mentioned data flow metrics, usually do not sufficiently capture the syntax and semantics of the source code: 'Most traditional code metrics cannot distinguish code fragments if these fragments have the same structure and complexity, but implement a different functionality. For example, if we switch several lines in the code fragment, traditional features, such as the number of lines of code, number of function calls, and number of tokens, would remain the same. Therefore, semantic information is more important for defect prediction than these metrics' (Akimova et al., 2021).

However, there are at least three substantial reasons suggesting that DD can be a good defect predictor in the SDP models:

- DD correlates well with the developer's subjective sense of 'difficulty' to understand a source code (Katzmarski and Koschke, 2012),
- the same correlation was observed by direct measurement of developers' brain activity using fMRI (Peitek et al., 2020),
- DD is the only known metric that satisfies all nine Weyuker properties (Weyuker, 1988; Beyer and Häring, 2014).

The last reason is also the answer to Akimova's objection: it is true that metrics like lines of code or cyclomatic complexity do not distinguish the programs in which several lines of code were switched. However, one of the Weyuker properties of a well-designed metric requires exactly that there exist at least two programs, where one is created from the other by permuting some lines, and the metric is different for these two programs. The DD metric, in particular, fulfills this condition (Beyer and Häring, 2014).

Since, to our best knowledge, there is no research on DD regarding the SDP models, the natural next research steps are to verify if the data flow metrics are redundant with other classical source code metrics and to measure the importance of data flow metrics in such models. Apart from DD, in our research we will also investigate its composite variant proposed by us – dep-degree density (DDD), understood as DD divided by the number of logical lines of code. The justification for introducing this metric is given in Section 2.

Now we can formally state three research questions that we answer in this paper.

- RQ1. Do the DD and DDD metrics measure the same aspects of the source code as other classical source code metrics?
- RQ2. What is the importance of DD and DDD as features in SDP models?
- RQ3. How does the use of DD and DDD affect the performance of the model?

Although there are models that predict the actual number of residual defects, in this paper we consider classification models, which are the most common approach to defect prediction (Akimova et al., 2021). In these models, a prediction for a given source code element is 'yes' (if the model predicts at least one defect in the code) or 'no' otherwise.

The paper is organized as follows. In Section 2 we formally define the DD and the DDD proposed by us. In Section 3 we describe the results of experiments that answer the research questions RQ1–RQ3 about the correlation, importance of features, and predictive power of DD and DDD. Section 4 presents the threats to validity in our study. A discussion of the results and possible future research follows in Section 5.

2 DATA FLOW METRICS

To formally introduce the definition of DD, we need to define a data flow graph (DFG), a model built on the concept of a control flow graph, enriched with information on where the definitions and uses of variables occur. A *control flow graph* G = (S, E) is a directed graph, where *S* represents program operations, and $E \subseteq S \times S$ is a set of control flow edges of the program. A program operation may be either a variable declaration, an assignment operation, a conditional statement, a function call, or a function return. A *path* of length *k* in *G* is a sequence of nodes $(s_0, ..., s_k)$ such that $(\forall i \in \{0, ..., k - 1\}) (s_i, s_{i+1}) \in E$.

Program operations read and write values from/to variables. Each place in which a value of a variable v is stored into memory (because of defining or computing the variable's value) is called a *definition of S*. Each place in which a value of a variable v is read from memory is called a *use of v*.

Let *V* be the set of all variables (attributes and objects) of a given program *P* represented by a control flow graph G = (S, E). A *data flow graph* for *G* is a tuple $D_G = (S, E, def, use)$, where $def, use : S \rightarrow V$ are functions that store information about the definitions and uses of variables in different program operations:

- $(\forall v \in V)(\forall s \in S) \ v \in def(s) \Leftrightarrow v \text{ is defined in } s;$
- $(\forall v \in V)(\forall s \in S) \ v \in use(s) \Leftrightarrow v \text{ is used in } s.$

A path $p = (s_0, ..., s_k)$ in D_G is called a *du-path* for $v \in V$, if the following conditions are satisfied:

- $v \in def(s_0)$,
- $v \in use(s_k)$,
- $(\forall 1 \le i \le k-1) v \notin def(s_i).$

In other words, v is defined in s_0 , used in s_k , and there is no redefinition of v along p. Dep-degree metric (DD) is defined as the number of pairs (s,s') of operations such that there exists a du-path from s to s' for some variable v. Originally, DD was defined in terms of the number of nodes' out-degrees in a socalled dependency graph (Beyer and Fararooy, 2010). However, assuming that each operation contains at most one definition, we can reduce it to the problem of counting the du-paths in the code and define it as follows. Let G = (S, E) be a control flow graph with a set V of variables, and let $v \in V, s, s' \in S$. Let dup(v, s, s') = 1 iff there exists a du-path from s to s' for v; otherwise, dup(v, s, s') = 0. Then

$$DD(D_G) = \sum_{v \in V} \sum_{s \in S} \sum_{s' \in S} dup(v, s, s')$$

Beyer and Fararooy (Beyer and Fararooy, 2010) compare DD with two classical metrics: lines of code and cyclomatic complexity. They give several examples of pairs of programs with the same value of these two metrics, but differing in DD value, showing that DD is a good indicator of readability and understandability.

However, the opposite situation may also occur. DD may be 'insensitive' to program size. In Fig. 1 two equivalent programs are shown. Both have the same dep-degree (DD=16), but one is twice as long (10 LOC) than the other (5 LOC). The code on the left may be considered easier to understand because its lines contain simpler computations. However, this comes at the expense of more variables, definitions, and lines of code. The right program has fewer definitions and is shorter, but this makes it more 'dense,' which may cause more difficulties for a programmer to understand it, and hence makes it more error-prone.

It is easy to provide a similar example in the case of cyclomatic complexity, showing the possible insensitivity of DD to program structural complexity. Two programs can have the same DD but differ in cyclomatic complexity.

To grasp the concept of data flow 'density' we introduce a new metric called *dep-degree density* (DDD). It is defined as the value of DD divided by the logical lines of code: DDD = DD/LLOC. Since we consider code metrics on the class level, by LLOC we understand the number of non-empty and non-comment code lines of the class, including the non-empty and non-comment code lines of its local methods, anonymous, local, and nested classes (to measure it we use the TLLOC metric from Open Static Analyzer).

3 EXPERIMENTS

In this section we present the experimental results on investigating the correlation, feature importance, and predictive power of DD and DDD metrics in the SDP models.



Figure 1: Two equivalent programs with the same DD but different LOC.

Notice that in this research we *do not* intend to investigate relations between metrics, examine the influence of a given resampling method in the training process, choose the best possible set of metrics, find the best possible SDP model in terms of different performance measures, compare the models obtained with other models from the literature, etc. Our intention is only to verify if DD and DDD metrics can be useful in defect prediction, that is, if they have a positive influence on the SDP model performance. Other aims mentioned above are an important but separate issue, out of the scope of this research. Since DD and DDD are static code metrics, we compare them with other such metrics, not with process metrics or product metrics.

3.1 Datasets and Metrics Used

For our experiments, we selected bug data from nine JAVA projects from the GitHub Bug Dataset. The data are part of the Unified Bug Dataset (Ferenc et al., 2020). The overview of the selected projects is shown in Table 1. Each file is described with a set of 62 metrics measured by the Open Static Analyzer (github.com/sed-inf-uszeged/OpenStaticAnalyzer). 52 of them are classlevel metrics (incl. 4 complexity metrics, 5 coupling metrics, 8 documentation metrics, 5 inheritance metrics, 30 size metrics), 9 are code duplication metrics, and one (cyclomatic complexity) is a complexity metric computed at the file level. For detailed definitions of these metrics, see the Open Static Analyzer documentation.

For each file in the database, we added two data flow metrics described above: DD and DDD. DD was

Table 1: Overview of the selected projects. kLLOC = size in kilo Logical Lines of Code.

Project	kLLOC	Classes	Bug	% bug
el elasticsearch	219.4	2781	445	16.0
hz hazelcast	112.5	1809	276	15.3
br broadleaf	59.8	1272	274	21.5
ti titan	57.9	787	66	8.4
ne netty	35.6	732	219	29.9
ce ceylon	78.0	678	55	8.1
or oryx	12.3	263	43	16.3
cm cMMO	11.0	248	57	23.0
md mapdb	35.7	133	20	15.0

measured using the AntLR tool, which returns the abstract syntax tree (AST) of the source code. To calculate DD, we transformed the resulting ASTs into data flow graphs and measured DD using the classical iterative technique of computing the data flow equations (Kennedy, 1979), which allowed us to calculate the reachability of each variable in each statement of the source code and count the number of resulting dupaths.

3.2 Correlation Analysis

Recent studies show that eliminating correlated metrics improves the consistency of the rankings produced and impacts model performance. Thus, when one wishes to derive a sound interpretation from the defect models, the correlated metrics must be mitigated (Tantithamthavorn et al., 2016; Tantithamthavorn and Hassan, 2018; Jiarpakdee et al., 2021). Therefore, the natural question arises: Are DD and DDD correlated with other metrics?

To verify this and to answer RQ1, we used the

AutoSpearman method (Jiarpakdee et al., 2018), implemented in the R package Rnalytica, with default parameters (threshold = 0.7, vif = 5), as well as a direct analysis of the correlation of DD and DDD with other source code metrics. Correlation analysis allows us to verify whether two metrics measure the same or different aspects of the source code. A very high correlation between two metrics m_1 and m_2 suggests that they measure similar code characteristics, so it is not necessary to use them both in a SDP model. In this way, we also reduce the number of variables without significantly reducing the model performance. On the other hand, very low correlation suggests that m_1 and m_2 measure substantially different aspects of the code, so both should be included in the SDP model, increasing its performance.

We applied AutoSpearman to the entire Unified Bug Dataset with DD and DDD metrics added. It returned 17 (out of 64) least correlated metrics: CLC, LCOM5, NLE, CBO, CBOI, AD, PUA, NOC, NLA, NLG, NLPA, NLS, NPA, NPM, NS and dep-degree density (DDD). This allows us to claim that DDD measures different code aspects than other static code metrics. An interesting fact is that AutoSpearman did not choose cyclomatic complexity, which is a very popular complexity metric commonly used in software defect prediction models. The reason may be that it is very highly correlated with other metric returned by AutoSpearman, NLE – Nesting Level Else-If (correlation 0.82).

We also investigated the correlation between the data flow metrics and all other metrics used in this study. In general, DDD turned out to be very weakly correlated with all other metrics. The correlation is also much weaker than in the case of DD. Fig. 2 presents the correlations of DD and DDD with all other metrics. Each point shows the correlation of some metric with DD (X-axis) and DDD (Y-axis) expressed in terms of Pearson correlation coefficient.

Only for seven metrics is the correlation with DDD greater than 0.3. These are: NL (0.421), NLE (0.401), TNOS (0.388), NOS (0.388), WMC (0.357), LLOC (0.302), and LOC (0.300). However, even for these metrics, the correlation is relatively weak. For DD, we obtained much stronger correlations. For eight metrics (McCC, TNOS, TLLOC, TLOC, NOS, LLOC, LOC, and WMC), the correlation is very high (between 0.8 and 0.9), for nine metrics (TNLM, RFC, NL, NLE, NLM, TNLPM, TNLA, NLPM, NLA) between 0.5 and 0.8, and for 16 others (NOI, CCO, LLDC, LDC, CI, TCLOC, CLOC, CBO, TNM, PUA, TNA, TNPM, NM, NATTR, TNLG, LCOM5) it is between 0.3 and 0.5. The correlation between DD and DDD is 0.52.



Figure 2: Pearson correlation coefficients for correlation of DD and DDD with other analyzed metrics.

This analysis answers RQ1: DDD measures aspects of the code different from any other metric measured by the Open Static Analyzer. DD, on the other hand, is very similar to at least nine other metrics.

3.3 Feature Importance

The importance of features describes how or to what extent each feature contributes to the prediction of the model. There are many approaches to measure it, but the most important features differ depending on the technique, and a combination of several explanation techniques could provide more reliable results (Saarela and Jauhiainen, 2021). Therefore, we used two approaches to calculate the importance of the features. The first one, the so-called filter approach, is model-agnostic. It is based on a ROC curve analysis for each predictor. The area under the ROC is used as a measure of variable importance. To perform the analysis, we used the filterVarImp function from the caret R package.

The analysis showed that the top ten (out of 64) features are: McCC (0.73), WMC (0.72), DD (0.70), TNOS (0.70), TLLOC, TLOC, NL, NLE (0.69), RFC, and TNLA (0.68). DDD was ranked 23rd (0.63).

In the second approach, we used the builtin importance measurement mechanism in the randomForest function. The total decrease in node impurities from splitting on the variable, averaged over all trees, is calculated. The node impurity is measured by the Gini index as follows. For each tree, the prediction accuracy on the out-of-bag portion of the data is recorded. Then the same is done after permuting each predictor variable. The difference between the two accuracies are then averaged over all trees, and normalized by the standard error. The results are shown in Fig. 3. DDD and DD metrics were ranked, respectively, as 5th (43.7) and 7th (40.8).

From both analyses, it seems that the DD and DDD metrics are of significant importance as defect predictors, which answers the RQ2. The results of the second analysis were used in the 'fixed metrics set' version of the experiment described in the following (see Section 3.4).



Figure 3: Variable importance - Gini index.

3.4 Experimental Design for the Within-Project Defect Prediction Experiment

To investigate the predictive power of data flow metrics in the within-project defect prediction setup, we performed the experiment on the nine abovementioned projects with five SDP models described below. The experimental design is shown in Fig. 4. The process described in this figure was repeated 100 times for each project and model.

Analysis of the distribution of the independent variables revealed their right skewness. To mitigate the skew, which introduces different orders of magnitude between variables, we performed the log transformation ln(x+1) for each independent variable (except for the density metrics, as they are always scaled to [0,1]) as suggested by (Menzies et al., 2007; Jiang et al., 2008).

The data set is unbalanced – from Table 1 we can see that the 'bugged' class accounts for only 8-30% of all data points. In (Tantithamthavorn et al., 2020), supported by significant empirical data from 101 proprietary and open source projects, the authors argue that rebalancing techniques are beneficial when the goal is to increase AUC and recall, but should be avoided when deriving knowledge and understanding from defect models. Since our primary goal is to verify the predictive power of the data flow metrics and not to build the well-performing SDP models, we intentionally did not use any rebalancing techniques.

The whole experiment was carried out twice, for two different feature selection strategies. The set of such selected metrics is denoted by X in Fig. 4. The first strategy uses the sets of non-correlated metrics selected in each iteration by AutoSpearman. In the second one, in all iterations we used the fixed set of ten most important metrics provided by the feature importance analysis (excluding DD and DDD) performed for the whole data set (see Section 3.3). These were (see Fig. 3): McCC, WMC, CBO, RFC, NOI, NOA, TNOS, TLOC, TLLOC and LOC.

In each iteration, the data set was split into training and test sets in 60%-40% proportions and the features (metrics) were selected. We trained five different SDP models: Logistic Regression (LR), Random Forests (RF), Naive Bayes (NB), k-Nearest Neighbors (KN), and Classification and Regression Trees -CART (CT). The choice was dictated by the fact that they are widely used by the machine learning community and have been widely used in many studies (Bowes et al., 2018). In addition, they are explainable and have built-in model explanation techniques (Hall et al., 2012; Tantithamthavorn et al., 2017). Moreover, they use distinct predictive techniques: Naive Bayes is a generative probabilistic model assuming conditional independence between variables; logistic regression is a discriminative probabilistic model that works well also for correlated variables; CART is an entropy-based model; random forest is an ensemble technique; kNN is a simple, nonparamtric, local, distance-relying approach. For the hyperparameter optimization training process, we used the R package caret and its function train(). We used the following models implemented in caret: glm, rf, naive_bayes, knn, and rpart.

Each of the five models was trained in four different configurations:

- using selected metrics only, with no data flow metrics (X)
- using metrics from X with DD added (DD)
- using metrics from X with DDD added (DDD)
- using metrics from X with both DD and DDD added (DD+DDD)

In the training process we used the .632 bootstrap, an enhancement to the out-of-sample bootstrap sampling technique. Recent studies show that out-ofsample bootstrap validation yields the best balance between the bias and variance of estimates among the 12 most commonly adopted model validation techniques for evaluation. The .632 variant corrects the downward bias in performance estimates (Efron, ENASE 2023 - 18th International Conference on Evaluation of Novel Approaches to Software Engineering



Figure 4: An overview diagram of the experimental design for our study.

1983; Tantithamthavorn et al., 2017). Using the bootstrap instead of a simple holdout or cross-validation approach leverages aspects of statistical inference.

Bowes (Bowes et al., 2018) suggests that researchers should repeat their experiments a sufficient number of times to avoid the 'flipping' effect that can skew prediction performance. The learning process was therefore repeated 100 times for each combination of model (5), configuration (4), and project (9). In each iteration we used different, randomly selected training and test sets. The model performance metrics were then averaged over 100 runs for each of the $5 \times 4 \times 9 = 180$ combinations. This approach mitigates the risk of bias in the test data and reduces bias in the model testing process. Moreover, the split procedure allowed us to maintain the same defective ratio in the training and test sets as in the original dataset, making them representative.

All models were validated on test data and their performance was compared in terms of F1 score, ROC-AUC and Matthew's Correlation Coefficient. Before we justify the choice of the performance measures, let us define them formally. A true positive (resp. negative) is an outcome when the model correctly predicts the positive ('bugged') (resp. negative ('no bug')) class. A false positive (resp. negative) is an outcome when the model incorrectly predicts the positive (resp. negative) class. Denote by TP, TN, FP, and FN the number of, respectively, true positive, true negative, false positive, and false negative outcomes. F1 Score. Precision is the ratio of TP and all elements classified as positive, TP+FP. Recall is the ratio of TP and the total number of elements belonging to the positive class, TP+FN. F1 score is the harmonic mean of precision and recall:

$F1 = 2 \times \frac{Precision \times Recall}{Precision + Recall}.$

F1 score varies from 0 (no precision or recall) to 1

(perfect classifier).

ROC-AUC. The *Area Under the Receiver Operating Characteristic Curve* measures the ability of the classifiers to discriminate between defective and nondefective examples (Rahman and Devanbu, 2013). The ROC curve is created by plotting the Precision against the Recall at various threshold settings. ROC-AUC is the area under this curve. A perfect classifier has ROC-AUC equal to 1, and a random one has ROC-AUC = 0.5.

Matthew's Correlation Coefficient (MCC). *MCC* is a measure of association for two binary variables defined as $MCC = \frac{TP \times TN - FP \times FN}{\sqrt{(TP+FP)(TP+FN)(TN+FP)(TN+FN)}}$. The MCC is a value between -1 (total disagreement between prediction and observation) and +1 (perfect classification). A classifier with no better prediction

than random has MCC = 0. F1 is a traditional performance metric, but it is sensitive to the threshold separating a defective from a non-defective example. Commonly, this threshold is configured to a probability of 0.5. However, this arbitrary configuration can introduce bias in the performance analysis. ROC-AUC, on the other hand, is unrestricted to this threshold and provides a single scalar value that balances the influence of precision (benefit) and recall (cost) (Ma et al., 2012). The ROC-AUC is also robust to class imbalance, which is frequently present in software defect prediction datasets, including the dataset used in this research. The MCC is a balance-independent metric and combines all quadrants of the binary confusion matrix (TP, TN, FP, FN), whereas the F1 measure is balancesensitive and ignores the proportion of TN. The MCC has been shown to be a reliable measure of the predictive performance of the model (Shepperd et al., 2014) and can be tested for statistical significance, with $\chi^2 = N \times MCC^2$, where N is the total number

of examples in the data set.

All three measures provide a single value that facilitates comparison between models. Since different metrics focus on different aspects of performance, a proper performance comparison requires the use of different measures.

3.5 Results of the Within-Project Defect Prediction Experiment

In the first version of the experiment, for each project and iteration, the set of uncorrelated metrics was selected by AutoSpearman from the set of all metrics, excluding DD and DDD. Its size ranged from 12 to 19. The most frequently selected metrics were: LCOM5 (100%), CBO (74%), NOP (73%), NOC, CBOI, NLA (69%), PUA, NLPA (64%), AD (62%), CC (53%), NL (50%).

Table 2 presents the results of this experiment. Notation used: Pr = project name, M = model (see Section 3.4 for full names), X = models trained without data flow metrics, DD = models trained with DD added, DDD = models trained with DDD added, DD+DDD = models trained with DD and DDD added.

In general (last row of the table summarizing the results for all projects and classifiers), models with no data flow metrics achieve the worst results in terms of all three performance measures (F1, ROC-AUC, MCC). Models using DDD are slightly better, followed by those that use DD. Models using both DD and DDD achieve the best results in terms of all three performance measures.

It is worth noticing that when allowing AutoSpearman to choose from the set of metrics including the data flow ones, it was always choosing DDD as one of the non-correlated metrics and has never indicated DD. However, the experiment results show that the models using DD perform better than the models using DDD. This may suggest that removing correlated metrics does not always lead us to the best choice of independent variables. The reason may be that two or more variables may be highly correlated, but their *interaction* with themselves or with other variables may be valuable information for the model and may significantly impact its performance.

In the second version of the experiment, we used the fixed set of metrics obtained from the feature importance analysis (see Fig. 3). The results, shown in Table 3, are similar: models with DD+DDD perform the best, followed by those that use only one data flow metric. Models without data flow metrics have the lowest performance. The results are worse than those of Table 2, because we used a smaller set of metrics.

For each performance measure we performed the paired t-test to check the statistical significance between the results of configuration X and the results obtained for configurations DD, DDD, and DD+DDD. The differences turned out to be statistically significant (p < 0.05) in all cases.

This experiment allows us to answer to RQ3 in the context of within-project SDP: adding the data flow metrics as the model predictors increases the model's performance in terms of all three performance metrics used.

4 THREATS TO VALIDITY

Construct Validity. The parameters of the learners influence the performance of the defect models. The hyperparameter optimization performed by caret is done using the train() function, which has its own parameters, like tuneLength which was always set to 5 in our experiments. This might have had an influence on the performance results.

Internal Validity. Although it is recommended to remove correlated variables, it may be the case that despite the high correlation between two or more variables, their *interaction* may be very meaningful and have a significant impact on defect prediction. We have experienced exactly this phenomenon when comparing the AutoSpearman results with the performance of the models using DD instead of DDD (see the discussion in Section 3.5). It is possible that a feature subset different from the one chosen by AutoSpearman could affect the performance of the model and, thus, our results. We mitigated this risk by performing the second experiment, with a fixed set of metrics resulting from the feature importance analysis.

We used 100 repetitions to draw reliable bootstrap estimates of the performance measures, but this requires a very high computational cost. It may be impractical for some compute-intensive ML models or models that use a large number of independent variables.

External Validity. Our experiments are based only on within-project prediction scenarios. We did not investigate cross-project prediction, just-in-time defect prediction (Pascarella et al., 2019) or heterogeneous defect prediction (Nam et al., 2018). The results may differ in these scenarios, and these models work better when process metrics are used. In our study we used static source code metrics only.

We investigated only nine JAVA projects from the Unified Bug Dataset. Predictions were made at the

						Doufourn	anos matrico (o	T across occurrent	(outer OO				
Ŧ	Σ		F1-5	score			ROC	AUC	(anni ao	Ŵ	atthew's Correl	lation Coefficie	nt
		x	DD	DDD	DD+DDD	x	DD	DDD	DD+DDD	x	DD	DDD	DD+DDD
	CT	$.634 \pm .040$	$.636\pm.046$	$.628 \pm .042$	$.630 \pm .047$	$.799 \pm .034$	$\textbf{.806}\pm\textbf{.031}$	$.798 \pm .034$	$.803 \pm .029$	$.560 \pm .046$	$.560 \pm .050$	$.560 \pm .046$	$.554 \pm .051$
_	Z :	$.625 \pm .040$	$.649 \pm .041$	$.624 \pm .041$	$.650 \pm .040$	$.846 \pm .021$	$.855 \pm .022$	$.847 \pm .020$	$.855 \pm .020$	$.553 \pm .046$	$.578 \pm .048$	$.553 \pm .046$	$.579 \pm .047$
DL	r K	$.606 \pm .036$ $.656 \pm .037$	$.601 \pm .037$ $.668 \pm .034$	$.608 \pm .034$.634 ± .033 660 ± 034	8.40 ± 0.023	$.838 \pm .023$ $.856 \pm .020$	$.851 \pm .023$ $.850 \pm .021$.843 ± .023 856 ± 020	$140. \pm 660.$	$583 \pm .045$	$140. \pm 650.$.503 ± .040 582 ± 041
	RF	$.683 \pm .039$	$.683 \pm .038$	$.679 \pm .038$	$.682 \pm .038$	$.874 \pm .020$	$875 \pm .019$	$875 \pm .019$	$875 \pm .019$	$.629 \pm .042$	$.629 \pm .041$	$.629 \pm .042$	$.631 \pm .040$
	L]	$.197 \pm .088$	$.191 \pm .082$	$.192 \pm .082$	$190 \pm .079$	$.618 \pm .069$	$.612 \pm .064$	$.614 \pm .069$	$.610 \pm .066$	$.174 \pm .091$	$.162 \pm .089$	$.174 \pm .091$	$.162 \pm .084$
	KN	0.090 ± 0.022	$.108 \pm .043$	$.094 \pm .030$	$.113 \pm .046$	$.721 \pm .049$	$.717 \pm .046$	$.720 \pm .052$	$.712 \pm .048$	$.141 \pm .055$	$.161 \pm .063$	$.141 \pm .055$	$.168 \pm .069$
e	LR	$.167 \pm .077$	$.165 \pm .075$	$.167 \pm .077$	$.184 \pm .080$	$.741 \pm .045$	$.737 \pm .046$	$.738 \pm .045$	$.738 \pm .045$	$.187\pm.088$	$.184\pm.087$	$.187 \pm .088$	$\textbf{.202} \pm \textbf{.089}$
	NB	$.199 \pm .070$	$.215 \pm .074$	$.209\pm.075$	$.222 \pm .076$	$.750 \pm .041$	$.753 \pm .040$	$.753 \pm .041$	$.754 \pm .042$	$.155\pm.078$	$.163 \pm .084$	$.155\pm.078$	$\textbf{.164} \pm \textbf{.083}$
	RF	$.125\pm.056$	$.145\pm.063$	$.133 \pm .056$	$.146 \pm .066$	$.778 \pm .044$	$.772 \pm .046$	$.775 \pm .044$	$.770 \pm .046$	$.172 \pm .077$	$.201 \pm .076$	$.172 \pm .077$	$.204 \pm .081$
	CT	$.392 \pm .051$	$.416 \pm .050$	$.388 \pm .046$	$.417 \pm .049$	$.723 \pm .038$	$.753 \pm .035$	$.718 \pm .038$	$.754 \pm .035$	$.346 \pm .045$	$.364 \pm .043$	$.346 \pm .045$	$.364 \pm .041$
	KN	$.427 \pm .039$	$.437 \pm .034$	$.427 \pm .036$	$.438\pm.035$	$.826 \pm .015$	$.842 \pm .014$	$.826 \pm .015$	$.842 \pm .014$	$.390 \pm .039$	$.387 \pm .035$	$.390 \pm .039$	$.388 \pm .035$
el	Ξ	$.388 \pm .030$	$.392 \pm .030$	$.387 \pm .030$	$393 \pm .030$	$.822 \pm .013$	$.834 \pm .013$	$.825 \pm .013$	$.834 \pm .013$	$.351 \pm .032$	$.346 \pm .031$	$.351 \pm .032$	$.347 \pm .031$
	NB D D D	$.308 \pm .044$	0.00 ± 0.00	$.351 \pm .042$	300 ± 1014 .	$.826 \pm .013$	$.534 \pm .012$	$.82/ \pm .013$	$.833 \pm .012$	$295 \pm .039$	$150. \pm 165.$	$295 \pm .039$	354 ± 035
	5	0c0. ± 664.	207 ± 2020	670. ± 674.	100 ± 101	$110. \pm 1/6.$	$110. \pm 7/6.$	$110. \pm 6/6.$	$110. \pm 6/6.$	050 - 900	$670. \pm 0.00$	050 - 000	070. ± 064.
	Z Z	$3.78 \pm .056$	$.382 \pm .047$	$0.00. \pm 785.$	$.384 \pm .048$	$240. \pm 690.$	$701 \pm .036$	$.042 \pm .042$	$./06 \pm .038$	$.328 \pm .050$	$.333 \pm .042$.328 ± .050	$.340 \pm .046$ $^{278} \pm .041$
۲ų		$.401 \pm .031$	323 ± 041	100. H 004.	330 ± 030	770 ± 007	$.781 \pm .024$	100 ± 101	1020 ± 020	286 ± 038	307 ± 041	$.360 \pm .042$ $286 \pm .038$	140. ± 9/5. 140 + 915
711	i g	301 + 040	$140. \pm 220.$	437 + 045	070 + 070 070 + 070	771 + 0.02	775 + 002	775 ± 0.03	$120. \pm 777$	335 + 046	348 + 045	335 ± 046	372 + 043
	RF	$424 \pm .042$	$.427 \pm .041$	$418 \pm .041$	420 ± 039	$.823 \pm .020$	$825 \pm .019$	$824 \pm .019$	824 + .019	$.411 \pm .041$	$.411 \pm .039$	$411 \pm .041$	408 ± 040
	E	431 + 104	420 + 107	421 + 109	474 + 109	718 + 055	714 + 060	725 + 059	777 + 0.64	311 + 110	295 + 114	311 + .110	$\frac{285 + 115}{285 + 115}$
	KN N	$349 \pm .095$	$387 \pm .095$	$359 \pm .098$	$390 \pm .094$	$.745 \pm .045$.771 + .045	.747 + .048	$.772 \pm .043$	$270 \pm .095$	303 ± 101	$270 \pm .095$	$309 \pm .096$
mc	Ľ	$.462 \pm .074$	$.492 \pm .075$	$.469 \pm .076$	$.484 \pm .082$	$.781 \pm .050$	$.786 \pm .049$	$.779 \pm .049$	$.786 \pm .048$	$.354 \pm .088$	$.381 \pm .090$	$.354 \pm .088$	$.368 \pm .097$
	RB	$.458 \pm .105$	$.490 \pm .086$	$.462 \pm .101$	$.506 \pm .085$	$.789 \pm .050$	$.796 \pm .047$	$.798 \pm .052$	$\textbf{.800} \pm \textbf{.049}$	$.357 \pm .111$	$.376 \pm .099$	$.357 \pm .111$	$.394 \pm .101$
	RF	$.413 \pm .082$	$.439 \pm .087$	$.428 \pm .091$	$.450\pm.095$	$.791 \pm .046$	$.797 \pm .043$	$.804 \pm .046$	$.804 \pm .044$	$.322 \pm .087$	$.353 \pm .096$	$.322\pm.087$	$.371 \pm .100$
	CT	$.558\pm.139$	$\textbf{.559} \pm \textbf{.138}$	$.558 \pm .139$	$.559\pm.138$	$.787 \pm .093$	$.786 \pm .094$	$.787 \pm .093$	$.786 \pm .094$	$.495 \pm .154$	$.494 \pm .154$	$.495 \pm .154$	$.494 \pm .154$
	KN	$.562\pm.154$	$.556\pm.170$	$.556 \pm .156$	$.568 \pm .157$	$\textbf{.866}\pm\textbf{.066}$	$.855 \pm .065$	$.863 \pm .072$	$.855 \pm .065$	$.533 \pm .149$	$.527 \pm .162$	$.533 \pm .149$	$.540 \pm .151$
pm	LR	$.493 \pm .150$	$.503 \pm .133$	$.505 \pm .139$.517 \pm .132	$.748 \pm .112$	$.747 \pm .104$	$.756 \pm .106$.758 \pm .093	$.417 \pm .169$	$.424 \pm .157$	$.417 \pm .169$	$.433 \pm .160$
	BN 1	$.596 \pm .116$	$.604 \pm .117$	$.592 \pm .114$	$.596 \pm .112$	$.813 \pm .083$	$.826 \pm .080$	$.814 \pm .079$	$.823 \pm .077$	$.534 \pm .137$	$.541 \pm .142$	$.534 \pm .137$	$.532 \pm .134$
	귀	$091. \pm 910$	0cl. ± 62c.	$.504 \pm .161$	$100 \pm .168$	$5 \text{ co.} \pm 688.$	+c0. ± 285.	$80. \pm 583$.	$40. \pm 188$	$.495 \pm .145$.499 ± .146	$.493 \pm .145$	$.488 \pm .154$
	U S	$.601 \pm .052$	$598 \pm .048$	$.597 \pm .056$	$594 \pm .047$	$.790 \pm .036$	$.787 \pm .035$	$.787 \pm .036$	$.786 \pm .033$	$.456 \pm .062$	$.450 \pm .060$	$.456 \pm .062$	$.445 \pm .059$
		$8.0. \pm 6.0.$	$150. \pm 100.$	140. ± 0.0.	$100. \pm 800.$	$170. \pm 108.$	220. ± 408.	770. ± 708.	100 ± 202	$100. \pm 040.$	$200. \pm 010.$	1c0. ± 04c.	$230. \pm 10.$
IIC	i B	514 ± 063	534 ± 054	537 + 056	545 ± 050	0.102 ± 0.020	1707 ± 1073	$120. \pm 20.1$	$120. \pm 0.01$	371 ± 053	385 ± 040	371 ± 053	200. H 24C.
	RF	$.689 \pm .045$	$.685 \pm .043$	$.689 \pm .043$	$.682 \pm .043$	$.899 \pm .016$	$897 \pm .017$	$.900 \pm .018$	$.896 \pm .018$	$.581 \pm .054$	$.577 \pm .051$	$.581 \pm .054$	$.574 \pm .052$
	CT	$.406\pm.108$.413 \pm .111	$.407 \pm .114$	$.408 \pm .117$	$.678 \pm .077$	$.679 \pm .078$	$\textbf{.682}\pm\textbf{.081}$	$.680 \pm .081$	$.336 \pm .124$	$.338 \pm .129$	$.336\pm.124$	$.331 \pm .132$
	KN	$.580\pm.101$	$.594 \pm .089$	$.580\pm.096$	$\textbf{.600} \pm \textbf{.088}$	$.864 \pm .049$	$.865 \pm .048$	$.866 \pm .048$	$.867 \pm .044$	$.529\pm.106$	$.550 \pm .096$	$.529\pm.106$.556 \pm .094
or	LR	$.534\pm.091$	$.537 \pm .094$	$.534\pm.081$	$.541 \pm .084$	$.843 \pm .049$	$.840 \pm .049$	$.841 \pm .049$. 843 ± . 049	$.462 \pm .103$	$.464 \pm .106$	$.462 \pm .103$	$.467 \pm .094$
	ЯВ	$.399 \pm .151$	$.413 \pm .148$	$.425 \pm .156$	$.442 \pm .150$	$.830 \pm .039$	$.842 \pm .037$	$.850 \pm .035$	$\textbf{.854}\pm\textbf{.036}$	$.367 \pm .148$	$.388 \pm .138$	$.367 \pm .148$	$.416 \pm .141$
	RF	$.570 \pm .090$	$.570 \pm .083$	$.565 \pm .093$	$.554 \pm .096$	$.879 \pm .042$	$.883 \pm .041$	$.883 \pm .042$. 886 ± . 040	$.537 \pm .095$	$.545 \pm .085$	$.537 \pm .095$	$.532 \pm .096$
	LT .	$.349 \pm .094$	$.349\pm.093$	$344 \pm .091$	$.345 \pm .089$	$.711 \pm .058$	$.714 \pm .056$	$.713 \pm .062$	$.712 \pm .062$	$.335 \pm .097$	$.336 \pm .094$	$.335 \pm .097$	$.331 \pm .092$
.1		0.14 ± 0.14	000 - 000 000 - 000	$10. \pm 014$.	4.50 ± 0.054	$.172 \pm .04$	$.109 \pm .049$	$.1/1 \pm .049$	915 + 0.12	$180. \pm 1070$	260. ± 224.	$180. \pm 104.$	0.001 ± 0.000
3	r R	$500. \pm 102$	226 ± 100	0.01 ± 100	$.292 \pm .009$	$.010 \pm .043$	743 ± 070	$.010 \pm .045$	$740. \pm 010$	$000. \pm 6/2.$	200 ± 002	$600. \pm 6/2.$	195 ± 100
	RF	$456 \pm .083$	431 + 088	425 + 081	405 + 085	831 + .039	828 + 040	827 ± 040	874 ± 003	496 + 072	474 + 076	$496 \pm .072$	454 ± 072
a		$442 \pm .172$	$452 \pm .168$	$445 \pm .169$	$455 \pm .167$	$794 \pm .076$	$798 \pm .076$	$796 \pm .077$	799 ± 076	$391 \pm .154$	$398 \pm .151$	$391 \pm .154$	$400 \pm .150$
1													

 $Table \ 2: \ Results \ of \ the \ within-project \ defect \ prediction \ experiment - feature \ selection \ done \ by \ AutoSpearman \ in \ each \ iteration.$

	ent	DD+DDD	$.535 \pm .047$	$.202 \pm .053$	0.12 ± 0.034	621 ± 035	$.145 \pm .092$.177 + .064	$.212 \pm .080$	$.183 \pm .054$	$.171 \pm .067$	$.272 \pm .044$	$.271 \pm .038$	$.290 \pm .029$	$.271 \pm .026$	$.352\pm.034$	$.301\pm.050$	$.349 \pm .039$	$.322 \pm .040$	$.308 \pm .035$	040. ± 206.	$.263 \pm .119$	$.525 \pm .095$	$.360 \pm .100$	305 ± 105 .	$.348 \pm .160$	$.346 \pm .170$	$.449 \pm .161$	$.411 \pm .126$	$.396 \pm .155$	$.431 \pm .054$	$.453 \pm .051$	$940. \pm 016.$	$.498 \pm .050$	$.310 \pm .112$	$.382 \pm .123$	$.355 \pm .106$	$.358 \pm .094$	$.445 \pm .098$	$.282 \pm .108$	$.338 \pm .079$	$.185 \pm .077$	$313 \pm .082$	$.336 \pm .139$
	lation Coeffici	DDD	$.537 \pm .047$	$.192 \pm .056$	250. ± 510.	$.454 \pm .025$	$130 \pm .081$	158 ± 061	$.162 \pm .084$	$.180 \pm .053$	$.145 \pm .066$	$.278 \pm .043$	$.261 \pm .036$	$.292 \pm .031$	$.266 \pm .026$	$.356 \pm .033$	$.284 \pm .044$	$.328 \pm .044$	$.322 \pm .039$	$.284 \pm .034$	140. ± ccc.	$111. \pm 772.$	$160. \pm 025$	$101. \pm 775$	303 + 003	$.353 \pm .163$	$.351 \pm .167$	$.463 \pm .156$	$.361 \pm .134$	$.428 \pm .162$	$.430 \pm .059$	$.445 \pm .043$	306 ± 046	.506 ± .053	$.310 \pm .108$	$.318 \pm .121$	$.254 \pm .106$	$.331 \pm .088$	$.434 \pm .111$	$.284 \pm .106$	$.356 \pm .080$	$180. \pm 771.$	$.058 \pm .078$	$.329 \pm .143$
	atthew's Corre	DD	$.529 \pm .052$	$.197 \pm .057$	1005 ± 006	$.622 \pm .036$	$.136 \pm .087$	171 + 062	$.169 \pm .080$	$.178 \pm .055$	$.151 \pm .067$	$.277 \pm .039$	$.266\pm.035$	$.293 \pm .028$	$.269\pm.025$	$.355\pm.032$	$.293 \pm .049$	$.344 \pm .043$	$.319 \pm .041$	$.286 \pm .034$	0+0. ± coc.	$.272 \pm .121$	$326. \pm 328$	$201. \pm 005.$	295 ± 085	$.348 \pm .160$	$.341 \pm .194$	$.448 \pm .158$	$.402 \pm .127$	$.427 \pm .158$	$.433 \pm .059$	$.452 \pm .047$	$.18 \pm .048$	$.498 \pm .049$	$.316 \pm .111$	$.382 \pm .114$	$.242 \pm .112$	$.326 \pm .094$	$.442 \pm .109$	$.283 \pm .107$	$.341 \pm .084$	080 ± 600	$700. \pm 680.$	$.330 \pm .143$
	M	×	$.537 \pm .047$	$.192 \pm .056$	$.000 \pm 0.00$	$.452 \pm .029$	$.130 \pm .081$	158 ± 061	$.162 \pm .084$	$.180 \pm .053$	$.145\pm.066$	$.278 \pm .043$	$.261 \pm .036$	$.292 \pm .031$	$.266\pm.026$	$.356\pm.033$	$.284 \pm .044$	$.328 \pm .044$	$.322 \pm .039$	$.284 \pm .034$	140. ± ccc.	$.277 \pm .111$	$160. \pm 025$	$101. \pm 772 \pm 0.084$	303 ± 003	$.353 \pm .163$	$.351\pm.167$	$.463 \pm .156$	$.361 \pm .134$	$.428 \pm .162$	$.430 \pm .059$	$.445 \pm .043$	$.319 \pm .048$ 306 ± 046	$.506 \pm .053$	$.310\pm.108$	$.318 \pm .121$	$.254 \pm .106$	$.331 \pm .088$	$.434 \pm .111$	$.284 \pm .106$	$.356 \pm .080$	$17.1 \pm .081$	$.056 \pm .001$	$.329 \pm .143$
00 runs)		DD+DDD	$.814 \pm .026$	$.690 \pm .062$	$8/1 \pm .018$	$878 \pm .015$	$624 \pm .067$	710 + 048	$.744 \pm .042$	$.748 \pm .039$	$.730 \pm .044$	$.695 \pm .044$	$.757 \pm .017$	$.804 \pm .013$	$.755 \pm .015$	$.831 \pm .013$	$.666 \pm .040$	$.729 \pm .025$	$.753 \pm .020$	$.745 \pm .021$	010. ± 00/.	$.696 \pm .054$	040 ± 7.040	$./84 \pm .043$ $801 \pm .038$	769 ± 0.03	$.732 \pm .096$	$\textbf{.825}\pm\textbf{.066}$	$.818\pm.113$	$.821 \pm .074$	$.833 \pm .065$	$.762 \pm .042$	$.808 \pm .022$	$910. \pm 6//.$	$.863 \pm .019$	$\textbf{.686} \pm \textbf{.073}$	$.774 \pm .058$	$.775 \pm .050$	$.797 \pm .054$	$\textbf{.831}\pm\textbf{.047}$	$.686 \pm .067$	$721 \pm .052$	$./81 \pm .047$	$./12 \pm .044$.768 ± .073
veraged over 10	AUC	DDD	$.814 \pm .025$	$.690 \pm .057$	$.8/1 \pm .019$	875 ± 015	$.622 \pm .066$	709 + 057	$.745 \pm .042$	$.750 \pm .040$	$.733 \pm .047$	$.696 \pm .048$	$.760 \pm .017$	$.804 \pm .013$	$.753 \pm .015$	$.833 \pm .013$	$.665 \pm .039$	$.704 \pm .024$	$.752 \pm .019$	$./43 \pm .022$	·/84 ± .018	$.700 \pm .054$	V20 ± 18/.	$./88 \pm .041$	$.772 \pm .042$	$.734 \pm .097$	$.809 \pm .073$	$.839 \pm .107$	$.816 \pm .073$	$.831 \pm .070$	$.758 \pm .043$	$.810 \pm .020$	610. ± 6//. ₽00 ± 002	$.866 \pm .018$	$.678 \pm .067$	$.763 \pm .059$	$.730 \pm .058$	$.804 \pm .054$	$.827 \pm .045$	$.686 \pm .066$	$.730 \pm .053$	$./81 \pm .045$	$.798 \pm .050$	$.767 \pm .074$
ance metrics (a	ROC-	DD	$.816 \pm .023$	$.688 \pm .060$	$.8/0 \pm .018$	875 ± 015	$.627 \pm .066$	707 + 048	$.741 \pm .041$	$.747 \pm .039$	$.728 \pm .049$	$.699\pm.043$	$.756 \pm .017$	$.804 \pm .013$	$.753 \pm .015$	$.831 \pm .012$	$.677 \pm .038$	$.726 \pm .026$	$.755 \pm .019$	784 ± 0.021	· / 84 ± .01 /	$.697 \pm .050$	$.//6 \pm .041$	$./80 \pm .042$ $708 \pm .038$	757 + .044	$.732 \pm .096$	$.822 \pm .068$	$.846\pm.103$	$.827 \pm .073$	$.837 \pm .065$	$.772 \pm .043$	$.808 \pm .022$	$610. \pm 677.$	$.866 \pm .018$	$.682 \pm .076$	$.773 \pm .058$	$.728 \pm .057$	$.777 \pm .053$	$.818 \pm .049$	$.688 \pm .066$	$123 \pm .051$	$(45) \pm .045$	$.794 \pm .051$	$.767 \pm .073$
Perform		x	$\textbf{.816} \pm \textbf{.022}$	930 ± 880	$0.01 \pm 1/6.$	870 ± 015	$.623 \pm .068$.711 + .057	$.741 \pm .040$	$.749 \pm .039$	$.731 \pm .049$	$.699 \pm .045$	$.757 \pm .017$	$.802 \pm .014$	$.750 \pm .015$	$.829 \pm .013$	$.669 \pm .038$	$.699 \pm .024$	$.742 \pm .019$	$.735 \pm .021$	$10. \pm 0.7$	$.699 \pm .050$	$./80 \pm .040$	$.700 \pm 038$	758 ± 044	$.734 \pm .097$	$.813 \pm .070$	$\textbf{.851}\pm\textbf{.100}$	$.817 \pm .079$	$.833 \pm .068$	$.769 \pm .043$	$.809 \pm .021$	$10. \pm 111$.869 ± .018	$.677 \pm .069$	$.760 \pm .058$	$.734 \pm .059$	$.780 \pm .054$	$.815 \pm .045$	$.690 \pm .064$	$.735 \pm .053$	$.788 \pm .044$	$.799 \pm .048$	$.766 \pm .074$
		DD+DDD	$.604 \pm .048$	$.197 \pm .057$	670 ± 080.	573 ± 032	$.183 \pm .082$	124 ± 048	$.176 \pm .065$	$.252 \pm .039$	$.138\pm.056$	$.329\pm.053$	$.321 \pm .041$	$.325\pm.030$	$.407 \pm .019$	$.387\pm.032$	$.348 \pm .060$	$.357 \pm .041$	$.328 \pm .038$	$.426 \pm .027$		$.411 \pm .106$	480. ± 104.	$.4/0 \pm .054$	427 ± 0.09	$.430 \pm .141$	$.394 \pm .155$	$.517 \pm .144$	$.501 \pm .097$	$.434 \pm .141$	$.584 \pm .048$	$.616 \pm .035$	$.400 \pm .040$	$.635 \pm .037$	$.393 \pm .112$	$.446 \pm .115$	$.414 \pm .100$	$.472 \pm .072$	$.465\pm.100$	$.299 \pm .103$	$.365 \pm .0/3$	970. ± 871.	.1 /0 ± .0 89	$.404\pm.162$
	core	DDD	$.606 \pm .052$	$.187 \pm .056$	$970. \pm 8/0.$	573 ± 035	$180 \pm .080$	111 + 044	$.152 \pm .060$	$.256 \pm .042$	$.130 \pm .052$	$.330\pm.056$	$.308\pm.037$	$.330 \pm .030$	$.408 \pm .019$	$.393\pm.033$	$.351 \pm .058$	$.357 \pm .047$	$.336 \pm .039$	$425 \pm .029$		$.415 \pm .107$	$.446 \pm .082$	$1060. \pm 100. \pm 200$	$432 \pm .090$	$.433 \pm .144$	$.403 \pm .141$	$.527 \pm .135$	$.485 \pm .099$	$.440 \pm .137$	$.583 \pm .049$	$.608 \pm .032$.40/ ± .042 603 ± 031	$.638 \pm .037$	$.390 \pm .111$	$.395\pm.120$	$.312 \pm .111$	$.480 \pm .070$	$.471 \pm .107$	$.301 \pm .101$	$.382 \pm .070$	$3/0. \pm 7/1.$	$.169 \pm .000$	$.401 \pm .164$
	F1-s(DD	$.605 \pm .057$	$190 \pm .058$	$870. \pm 6/0.$	$.500 \pm .010$	$.175 \pm .083$	$.126 \pm .049$	$.141 \pm .063$	$.248\pm.040$	$.125\pm.054$	$.334 \pm .048$	$.317 \pm .038$	$.327 \pm .030$	$.405 \pm .018$	$.392 \pm .031$	$.347 \pm .058$	$.353 \pm .042$	$.325 \pm .040$	$.409 \pm .027$	040. ± 040.	$.421 \pm .102$	9.00 ± 0.01	$.401 \pm .089$ $524 \pm .061$	415 ± 0.001	$.430 \pm .141$	$.398\pm.169$	$.514 \pm .148$	$.496 \pm .097$	$.466 \pm .148$	$.590 \pm .050$	$.615 \pm .033$	$.403 \pm .040$	$.637 \pm .038$	$.395 \pm .114$	$\textbf{.446} \pm \textbf{.108}$	$.288 \pm .110$	$.447 \pm .070$	$.468 \pm .110$	$.302 \pm .103$	$365 \pm .0/8$	$.166 \pm .080$	$321 \pm .084$	$.399 \pm .166$
		×	$.612 \pm .056$	$.185 \pm .057$	$870. \pm 6/0.$	5.73 ± 0.31	$168 \pm .076$	112 + 047	$.133 \pm .066$	$.251 \pm .039$	$.128 \pm .055$	$.334 \pm .051$	$.309 \pm .039$	$.325\pm.031$	$.403 \pm .019$	$.398 \pm .032$	$.335 \pm .052$	$.352 \pm .045$	$.316 \pm .039$	$.406 \pm .027$	$900. \pm 200.$	$.424 \pm .095$	$.448 \pm .082$.4/4 ± .080 538 ± 061	426 + 085	$.433 \pm .144$	$.415\pm.148$	$.524 \pm .147$	$.465 \pm .103$	$.467 \pm .150$	$.586 \pm .052$	$.605 \pm .030$	$.408 \pm .041$.643 ± .040	$.389 \pm .112$	$.376 \pm .130$	$.295 \pm .111$	$.449 \pm .068$	$.470 \pm .111$	$303\pm.100$	$371 \pm .073$	$.166 \pm .081$	$315 \pm .080$	$.397 \pm .167$
	Pr M		br CT	KN K	LK	RF	ce CT	KN KN	LR	NB	RF	el CT	KN	LR	NB	RF	hz CT	kn K	LR	NB	RF	mc CT	N N N	LK	RF	md CT	KN	LR	NB	RF	ne CT	KN	LK	RF	or CT	KN	LR	NB	RF	ti CT	KN K	ĽK	RF	all

Table 3: Results of the within-project defect prediction experiment - feature set fixed based on feature importance analysis.

class level. The results may be different for projects of different sizes, maturity, or written in other languages. They may also differ when performed at the method or file level.

5 CONCLUSIONS AND FUTURE WORK

In this paper we investigated the predictive power of two data flow metrics: dep-degree and dep-degree density. DDD measures different aspects of the code than other metrics considered, since it is weakly correlated with other metrics. DD shows significantly greater correlations. However, using DDD in SDP models only slightly increases the model performance. On the other hand, DD achieves much better results, but the best results were achieved for models that used both DD and DDD as independent variables.

To conclude, DD and DDD seem to be the interesting choice as defect predictors in the SDP models, as well as the objects of future research regarding SDP. They may also be used as useful code complexity metrics, indicating how difficult the code is to understand by the developer. It would also be interesting to investigate their predictive power in just-intime defect prediction models, which recently gained a lot of attention from researchers.

Data Availability. The source files (bug data, R script, and Open Static Analyzer metrics definitions) can be found at https://github.com/Software-Engineering-Jagiellonian/DepDegree-ENASE2023.

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